

# Resource Summary Report

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## Jeol: JEM-2100 Electron Microscope

RRID:SCR\_028490

Type: Tool

### Proper Citation

Jeol: JEM-2100 Electron Microscope (RRID:SCR\_028490)

### Resource Information

**URL:** <https://www.jeol.com/products/scientific/tem/JEM-2100.php>

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**Description:** JEOL JEM-2100 is a versatile, 200 kV transmission electron microscope (TEM) designed for high-resolution imaging and structural analysis across materials, nanotechnology, and biological sciences. It allows researchers to visualize nanoscale structures, perform chemical composition mapping, and analyze atomic crystal lattices.

**Synonyms:** , JEM-2100, JEM-2100 Electron Microscope, JEOL JEM-2100

**Resource Type:** instrument resource

**Keywords:** Japan Electron Optics Laboratory, transmission electron microscope,

**Specification URL:** [https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR\\_028490.pdf](https://raw.githubusercontent.com/SciCrunch/RRID-Instruments/refs/heads/main/PDF/SCR_028490.pdf)

**Resource Name:** Jeol: JEM-2100 Electron Microscope

**Resource ID:** SCR\_028490

**Alternate IDs:** Model\_Number\_JEOL\_JEM-2100

**Record Creation Time:** 20260529T042811+0000

**Record Last Update:** 20260905T133613+0000

### Ratings and Alerts

No rating or validation information has been found for Jeol: JEM-2100 Electron Microscope.

No alerts have been found for Jeol: JEM-2100 Electron Microscope.

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## Data and Source Information

**Source:** [SciCrunch Registry](#)

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## Usage and Citation Metrics

We have not found any literature mentions for this resource.